

Notice of References Cited	Application/Control No. 10/691,966	Applicant(s)/Patent Under Reexamination ABDEL-HAFEZ ET AL.	
	Examiner John P Trimmings	Art Unit 2133	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,510,534	01-2003	Nadeau-Dostie et al.	714/724
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	D	US-5,132,974	07-1992	Rosales, Barry C.	714/731
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Narayanan, S. et al., "An Efficient Scheme to Diagnose Scan Chanis", Test Conference 1997, 1-6 Nov 1997, pp 704-713. ✓
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.